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Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023 Based on structural similarity

Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 T TEST Pre- and # E1 Electrica		BZX8450-C5V1-Q Part Description Nexperia DHAM SMD package Test Conditions	Zener					
Assembly reliability labs Based on AEC-Q101 T TEST Pre- and	est	Nexperia DHAM SMD package						
Based on AEC-Q101 T TEST Pre- and	est	SMD package						
Based on AEC-Q101 T TEST Pre- and	est		Duration					
TEST Pre- and		Test Conditions	Duration	SMD package				
Pre- and	Post-Stress		Duration	# Lots	# Quantity	# Rejects		
# E1 Electrica								
	l Test	Tamb = 25 °C	N/A	see below	all parts	see below		
# A1 Precondi	tioning	JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	1514	64430	0		
HTRB High Ter # B1 Bias	nperature Reverse	MIL-STD-750-1 M1038 Method A Tj = Tjmax, VR = 80 % of rated reverse voltage	1000 hours	250	11400	0		
SSOP # B1b Steady S	State Operational	MIL-STD-750-1 M1038 Method B Tj = Tjmax, Iz = 100% of max. datasheet reverse current	1000 hours	44	1920	0		
# A4 Tempera	ature Cycling	JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	1000 cycles	311	14080	0		
UHAST # A3 or Unbiased	HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %		211	1 4000	0		
AC # A3 alt Autoclav	e	JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)	—96 hours	311	14080	0		
	midity High Iture Reverse Bias	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage ^[1]	1000 hours	311	14080	0		
IOL # A5 Intermit	tent Operating Life	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔTj = 100 °C for 15000 cycles	1000 hours	312	14120	0		
RSH # C8 Resistan	ce to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 c	269	8070	0		
# C8 Resistant SD # C10 Solderat		J-STD-002	10 s	19	6660	0		

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

2,68E+09
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